

Լեզուների իմացություն

Հայերեն English Русский Українська

Publications

Հոդված

Analytics for AI Related Applications of Multidimensional Multitape Finite Automata

Samvel SHOUKOURIAN, Tigran GRIGORYAN, Sevak AMIRKHANYAN

Electronics, Communications and Networks 2023 49-60

Հոդված

Functional Safety Compliant Test & Repair Framework for System-on-Chip Lifecycle Management

S. Shoukourian, G. Harutyunyan, G. Tshagharyan, Y. Zorian

Mathematical Problems of Computer Science 2021 7-17

Հոդված

Polynomial algorithm for equivalence problem of deterministic multitape finite automata

Samvel K. Shoukourian, Hayk A. Grigoryan

Theoretical Computer Science 2020 120-132

Հոդված

Memory Physical Aware Multi-Level Fault Diagnosis Flow

SAMVEL SHOUKOURIAN, GURGEN HARUTYUNYAN, SUREN MARTIROSYAN, YERVANT ZORIAN

IEEE Transactions on Emerging Topics in Computing 2020 700-711

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Fault Awareness for Memory BIST Architecture Shaped by Multidimensional Prediction Mechanism

S. Shoukourian, G. Harutyunyan, Y. Zorian

IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems 2019 562-575

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Experimental study on Hamming and Hsiao Codes in the Context of Embedded Applications

S. Shoukourian, G. Harutyunyan, G. Tshagharyan, Y. Zorian

IEEE East-West Design & Test Symposium 2017 25-28

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Automated Flow for Test Pattern Creation for IPs in SoC

S. Shoukourian, G. Harutyunyan, D. Sargsyan, Y. Zorian

IEEE East-West Design & Test Symposium 2017 21-24

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An Efficient Testing Methodology for Embedded Flash Memories

S. Shoukourian, G. Harutyunyan, S. Martirosyan, Y. Zorian

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Security Issues in Test and Repair Infrastructure for Systems-on-Chip

S. Shoukourian, G. Harutyunyan, G. Tshagharyan

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Գիտաժողովի կյուբ

An efficient approach for memory repair by reducing the number of spares.

Vrezh Sargsyan, Valery A. Vardanian, Samvel K. Shoukourian, Yervant Zorian, Avetik Yessayan

Գիտաժողովի կյուբ

Extending fault periodicity table for testing faults in memories under 20nm.

Gurgen Harutyunyan, Samvel K. Shoukourian, Valery A. Vardanian, Yervant Zorian

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A power based memory BIST grouping methodology.

Lusine Martirosyan, Gurgen Harutyunyan, Samvel K. Shoukourian, Yervant Zorian

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Overview study on fault modeling and test methodology development for FinFET-based memories.

Grigor Tshagharyan, Gurgen Harutyunyan, Samvel K. Shoukourian, Yervant Zorian

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Securing Test Infrastructure of System-on-Chips

S. Shoukourian, G.Tshagharyan, G.Harutyunyan, Y.Zorin

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Armenia: Communicating to World Community in Electronic Test and Design

Samvel Shoukourian, Yuri Shoukourian, Vladimir Sahakyan

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Testing Electronic Memories Based on Fault and Test Algorithm Periodicity

S. Shoukourian, G. Harutyunyan, V. Vardanian, A. Hakhumyan, Y. Zorian

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FINFET-BASED MEMORY TESTING USING MULTIPLE READ OPERATIONS

Samvel Shoukourian, Gurgen Harutyunyan, Grigor Tshagharyan, Yervant Zorian

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DETECTION OF ADDRESS ERRORS IN MEMORY DEVICES USING MULTI-SEGMENT ERROR DETECTION CODES

Samvel Shoukourian, Gurgen Harutyunyan, Hayk Grigoryan, Grigor Tshagharyan, Yervant Zorian
